IEEE EDS Kansai Chapter Awards 2013

IEEE EDS Kansai Chapter of the Year of the Year Award

Authors: Tatsuo Morita
Title: “GaN Gate Injection Transistor with Integrated Si Schottky Barrier Diode for Highly Efficient DC-DC Converters”
Affiliation: Panasonic Corp.

IEEE EDS Kansai Chapter MFSK Award

Authors: Takashi Matsumoto¹
Title: “Impact of Random Telegraph Noise on CMOS Logic Delay Uncertainty under Low Voltage Operation”
Coauthors: K. Kobayashi²,³ and H. Onodera¹,³
Affiliation: ¹Kyoto Univ., ²Kyoto Inst. Tech., ³JST CREST
IEEE EDS Kansai Chapter IMFEDK Best Paper Award

Authors: Yasufumi Kawai, Shuichi Nagai, Takeshi Fukuda, Nobuyuki Otsuka, and Daisuke Ueda
Paper-ID: B-2
Title: “A Compact Isolated Gate Driver using GaN HFETs on Sapphire Substrate Integrated with a 5.8GHz Electro-Magnetic Resonant Coupler”
Affiliation: Panasonic Corp.

IEEE EDS Kansai Chapter IMFEDK Student Paper Award

Authors: Indra Nur Adisusilo
Paper-ID: PA-01
Title: “Monte Carlo Simulation of Seebeck Coefficient of Si Nanostructure with Barrier Layers”
Coauthors: K. Kukita and Y. Kamakura
Affiliation: 1Osaka Univ, 2CREST

Authors: Kazuya Mukai
Paper-ID: PB-01
Title: “Growth of a sputtered Ta$_2$O$_5$/ZnO film and its application to an ion-sensitive field-effect transistor”
Coauthors: T. Onaka, K. Koike, T. Maemoto, S. Sasa, M. Yano, S. Kadokura, and Y. Nakamitsu
Affiliation: 1Osaka Inst. Tech., 2FTS Corp.

Authors: Takayuki Kadonome
Paper-ID: PC-01
Title: “Retinal Prosthesis of Frequency Modulation using Thin-Film Photo Transistors”
Coauthors: A. Matsumura, T. Higashiyama, S. Oyama, and M. Kimura
Affiliation: Ryukoku Univ.
Authors: **Daiki Sato**  
Paper-ID: PA-02  
Title: “Scaling Scheme Prospect of XCT-SOI MOSFET Aiming at Medical Implant Applications Showing a Long Lifetime with a Small Battery”  
Coauthors: Y. Omura  
Affiliation: Kansai Univ.

Authors: **Satoru Sasaki**  
Paper-ID: PC-02  
Title: “Fabrication of zinc oxide transparent thin film transistors on glass substrates by sol-gel method”  
Coauthors: S. Sasa, K. Ogata, and T. Maemoto  
Affiliation: Osaka Inst. Tech.

Authors: **Keisuke Kado**  
Paper-ID: C-4  
Title: “Evaluation of TaOₓ Nanoparticles for Resistive Random Access Memory”  
Affiliation: ¹NAIST, ²CREST